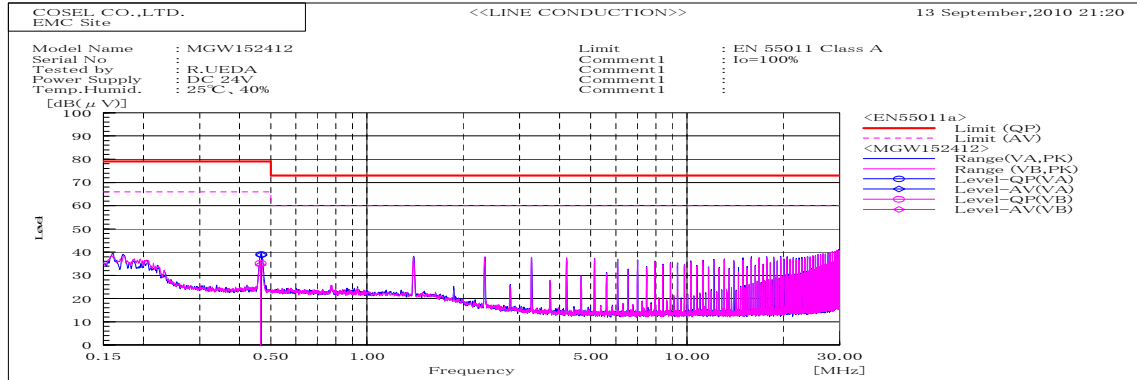
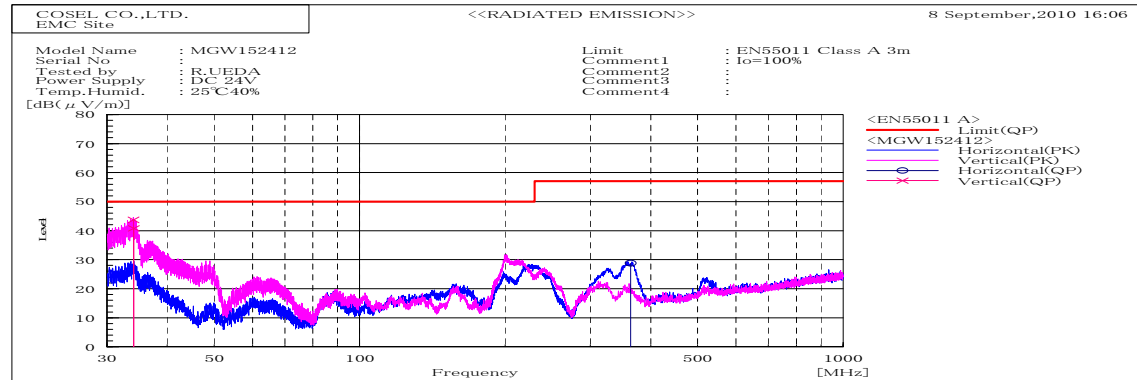


DATA SHEET		Date	21-Sep-10
Model	MGW152412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46523		VB	25.2	24.4	10	35.2	34.4	79	66	43.8	31.6	Pass	
0.46765		VA	28.9	28.7	10.1	39	38.8	79	66	40	27.2	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
34.049	V	Stable	59.2		-15.5	43.7		50	6.3	Pass	120	4	
34.103	V	Stable	56.3		-15.5	40.8		50	9.2	Pass	104	37	
363.235	H	Stable	44.6		-15.8	28.8		57	28.2	Pass	108	188	

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



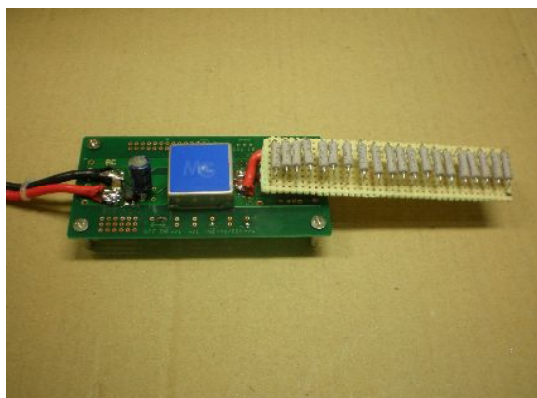


Conditions

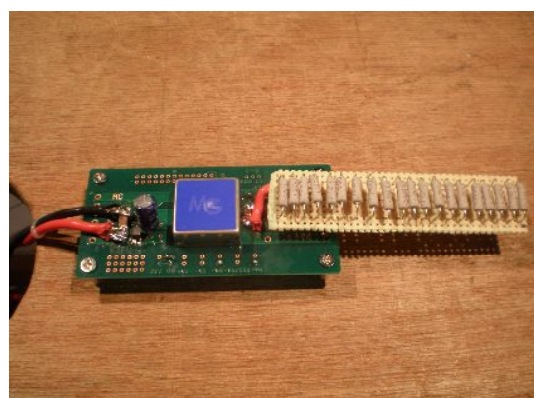
Test : EMI
Model Name : MGS1524□□/MGW1524□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

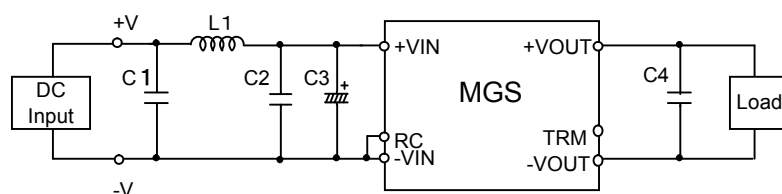


Fig.1 Testing circuitry 1

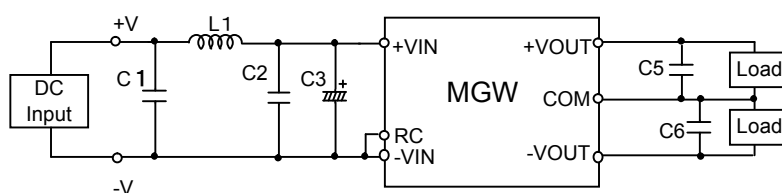


Fig.2 Testing circuitry 2

L1	:	2.2 μ H	CI4C-2R2	(KORIN ELECTRONICS)
C1,C2	:	50V 6.8 μ F	C4532X7R1H685MT	(TDK)
C3	:	50V 100 μ F	LXZ50VB100M	(NIPPON CHEMI-CON)
C4,C5,C6	:	25V 22 μ F	CM32X5R226K25A	(KYOCERA)